

USR Semiconductor Co., Ltd

SYMBOL	CHARACTERISTIC	TEST CONDITIONS	T_j (°C)	VALUE			UNIT
				Min	Type	Max	
$I_{T(AV)}$	Mean on-state current	180° half sine wave 50Hz Double side cooled, $T_{hs}=55^\circ C$	115			2517	A
$I_{T(AV)}$	Mean on-state current	180° half sine wave 50Hz Double side cooled, $T_{hs}=80^\circ C$	115			1690	A
V_{DRM} V_{RRM}	Repetitive peak off-state voltage Repetitive peak reverse voltage	$V_{DRM} \& V_{RRM}$ tp=10ms $V_{DsM} \& V_{RsM} = V_{DRM} \& V_{RRM} + 100V$ respectively	115	800		1800	V
I_{DRM} I_{RRM}	Repetitive peak current	at V_{DRM} at V_{RRM}	115			200	mA
I_{TSM}	Surge on-state current	10ms half sine wave	115			29	KA
I^2T	I^2T for fusing coordination	$V_R=0.6V_{RRM}$				4205	A^2s*10^3
V_{TO}	Threshold voltage		115			1.30	V
r_T	On-state slop resistance					0.14	$m\Omega$
V_{TM}	Peak on-state voltage	$I_{TM}=5000A$, $F=40KN$	115			2.00	V
dv/dt	Critical rate of rise of off-state voltage	$V_{DM}=0.67V_{DRM}$	115			500	$V/\mu s$
di/dt	Critical rate of rise of on-state current	From 67% V_{DRM} to 1500A, Gate source 1.5A $t_r \leq 0.5\mu s$ Repetitive	115			600	$A/\mu s$
I_{rm}	Reverse recovery current	$I_{TM}=1000A$, tp=1000 μs , $di/dt=-40A/\mu s$, $V_R=50V$	115			178	A
t_{rr}	Reverse recovery time					10.5	μs
Q_{rr}	Recovery charge					934	μC
t_q	Circuit commutated turn-off time	$I_{TM}=1000A$, tp=1000 μs , $V_R=50V$ $dv/dt=30V/\mu s$, $di/dt=-40A/\mu s$	115	15		40	μs
I_{GT}	Gate trigger current	$V_A=12V$, $I_A=1A$	25			450	mA
V_{GT}	Gate trigger voltage			0.9		4.5	V
I_H	Holding current			20		1000	mA
V_{GD}	Non-trigger gate voltage	At 67% V_{DRM}	115			0.3	V
$R_{th(j-h)}$	Thermal resistance Junction to heatsink	At 180° sine double side cooled Clamping force 40KN				0.011	$^\circ C / W$
F_m	Mounting force					35	KN
T_{stg}	Stored temperature				-40	140	$^\circ C$
W_t	Weight					1100	g
Outline	KT73cT						

Outline

